

Profiled bar transmission gratings: soft-x-ray calibration of new Kirchoff solutions—erratum

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In the original publication [Hettrick *et al.*, Appl. Opt., **43**, 3772–3796 (2004)], Eq. (6) and Fig. 30 were not presented properly. These misprints are corrected here. © 2004 Optical Society of America
OCIS codes: 050.1950, 050.1960, 300.6560.

In the top of the right column¹ of page 3775, Eq. (6) was inaccurately displayed. The correct form is presented here.

$$\eta_m = (S_R/S_G) \times (\text{GRAT}_{m_ON} - \text{GRAT}_{m_OFF} - \text{GRAT}_{m_BASE}) / (\text{SLIT}_{ON} - \text{SLIT}_{OFF}), \quad (6)$$

Also, on page 3792, top left column, the vertical axis of Fig. 30 was cut off. The figure as it should have been presented is shown here.

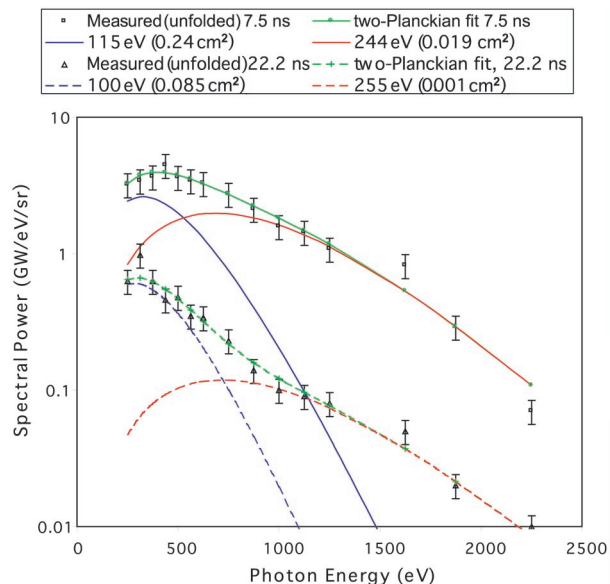


Fig. 30. Unfolded (gigawatt per electron volt per steradian) spectra of a Z-pinch source from experiment Z987, with grating HS14_Z on TGS5, viewing 0.40 height of the pinch at an angle of 13.5°. Data error bars are $\pm 20\%$. To obtain power observable at a viewing angle of 0°, multiply the vertical scale by a factor of $1/\cos(13.5^\circ) = 1.03$, since the high mass tungsten Z-pinch source is assumed to be Lambertian (optically thick). For the power spectrum observable from the full height of the pinch, divide the vertical scale by $f \sim 0.40$.

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Received 9 July 2004; accepted 9 July 2004.

0003-6935/04/254785-01\$15.00/0

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Reference

1. M. C. Hettrick, M. E. Cuneo, J. L. Porter, L. E. Ruggles, W. W. Simpson, M. F. Vargas, and D. F. Wenger, "Profiled bar transmission gratings: soft-x-ray calibration of new Kirchoff solutions," Appl. Opt. **43**, 3772–3796 (2004).